

Woojin Jeon

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The third column is the impact factor (IF) of the journal, and the fourth column is the number of citations of the article.

61
papers

1,320
citations

19
h-index

35
g-index

63
ext. papers

1,534
ext. citations

6.2
avg, IF

4.52
L-index

#	Paper	IF	Citations
61	Highly improved uniformity in the resistive switching parameters of TiO ₂ thin films by inserting Ru nanodots. <i>Advanced Materials</i> , 2013 , 25, 1987-92	24	152
60	32 B2 Crossbar Array Resistive Memory Composed of a Stacked Schottky Diode and Unipolar Resistive Memory. <i>Advanced Functional Materials</i> , 2013 , 23, 1440-1449	15.6	136
59	Grain size engineering for ferroelectric Hf _{0.5} Zr _{0.5} O ₂ films by an insertion of Al ₂ O ₃ interlayer. <i>Applied Physics Letters</i> , 2014 , 105, 192903	3.4	134
58	Ferroelectric properties and switching endurance of Hf _{0.5} Zr _{0.5} O ₂ films on TiN bottom and TiN or RuO ₂ top electrodes. <i>Physica Status Solidi - Rapid Research Letters</i> , 2014 , 8, 532-535	2.5	102
57	High-concentration boron doping of graphene nanoplatelets by simple thermal annealing and their supercapacitive properties. <i>Scientific Reports</i> , 2015 , 5, 9817	4.9	86
56	Atomic Layer Deposition of SrTiO ₃ Films with Cyclopentadienyl-Based Precursors for Metal Insulator Metal Capacitors. <i>Chemistry of Materials</i> , 2013 , 25, 953-961	9.6	61
55	Titanium dioxide thin films for next-generation memory devices. <i>Journal of Materials Research</i> , 2013 , 28, 313-325	2.5	56
54	Structure and electrical properties of Al-doped HfO ₂ and ZrO ₂ films grown via atomic layer deposition on Mo electrodes. <i>ACS Applied Materials & Interfaces</i> , 2014 , 6, 22474-82	9.5	48
53	Frustration of Negative Capacitance in Al ₂ O ₃ /BaTiO ₃ Bilayer Structure. <i>Scientific Reports</i> , 2016 , 6, 19039	4.9	37
52	Wafer-Scale Synthesis of Reliable High-Mobility Molybdenum Disulfide Thin Films via Inhibitor-Utilizing Atomic Layer Deposition. <i>Advanced Materials</i> , 2017 , 29, 1703031	24	33
51	TiO ₂ /Al ₂ O ₃ /TiO ₂ Nanolaminated Thin Films for DRAM Capacitor Deposited by Plasma-Enhanced Atomic Layer Deposition. <i>Electrochemical and Solid-State Letters</i> , 2008 , 11, H19		30
50	Improved Initial Growth Behavior of SrO and SrTiO ₃ Films Grown by Atomic Layer Deposition Using {Sr(demamp)(tmhd)} ₂ as Sr-Precursor. <i>Chemistry of Materials</i> , 2015 , 27, 3881-3891	9.6	29
49	Interfacial charge-induced polarization switching in Al ₂ O ₃ /Pb(Zr,Ti)O ₃ bi-layer. <i>Journal of Applied Physics</i> , 2015 , 118, 224105	2.5	24
48	High-throughput fabrication of infinitely long 10 nm slit arrays for terahertz applications. <i>Journal of Infrared, Millimeter, and Terahertz Waves</i> , 2015 , 36, 262-268	2.2	24
47	Growth of Conductive SrRuO ₃ Films by Combining Atomic Layer Deposited SrO and Chemical Vapor Deposited RuO ₂ Layers. <i>Chemistry of Materials</i> , 2012 , 24, 4686-4692	9.6	24
46	Evaluating the top electrode material for achieving an equivalent oxide thickness smaller than 0.4 nm from an Al-doped TiO ₂ film. <i>ACS Applied Materials & Interfaces</i> , 2014 , 6, 21632-7	9.5	23
45	Recent advances in the understanding of high-k dielectric materials deposited by atomic layer deposition for dynamic random-access memory capacitor applications. <i>Journal of Materials Research</i> , 2020 , 35, 775-794	2.5	23

44	Vapor Transport Synthesis of Two-Dimensional SnS ₂ Nanocrystals Using a SnS ₂ Precursor Obtained from the Sulfurization of SnO ₂ . <i>Crystal Growth and Design</i> , 2016 , 16, 3884-3889	3.5	19
43	Controlling the initial growth behavior of SrTiO ₃ films by interposing Al ₂ O ₃ layers between the film and the Ru substrate. <i>Journal of Materials Chemistry</i> , 2012 , 22, 15037		19
42	Controlling the Al-doping profile and accompanying electrical properties of rutile-phased TiO ₂ thin films. <i>ACS Applied Materials & Interfaces</i> , 2014 , 6, 7910-7	9.5	18
41	One-dimensional TiO ₂ @Ag nanoarchitectures with interface-mediated implementation of resistance-switching behavior in polymer nanocomposites. <i>ACS Applied Materials & Interfaces</i> , 2012 , 4, 5727-31	9.5	18
40	Impact of bimetal electrodes on dielectric properties of TiO ₂ and Al-doped TiO ₂ films. <i>ACS Applied Materials & Interfaces</i> , 2012 , 4, 4726-30	9.5	16
39	Quantitative Analysis of the Incorporation Behaviors of Sr and Ti Atoms During the Atomic Layer Deposition of SrTiO ₃ Thin Films. <i>ACS Applied Materials & Interfaces</i> , 2018 , 10, 8836-8844	9.5	15
38	Chemistry of active oxygen in RuO _x and its influence on the atomic layer deposition of TiO ₂ films. <i>Journal of Materials Chemistry C</i> , 2014 , 2, 9993-10001	7.1	15
37	Mesostructured Hf _x Al _y O ₂ Thin Films as Reliable and Robust Gate Dielectrics with Tunable Dielectric Constants for High-Performance Graphene-Based Transistors. <i>ACS Nano</i> , 2016 , 10, 6659-66	16.7	15
36	Controlling the Electrical Characteristics of ZrO ₂ /Al ₂ O ₃ /ZrO ₂ Capacitors by Adopting a Ru Top Electrode Grown via Atomic Layer Deposition. <i>Physica Status Solidi - Rapid Research Letters</i> , 2019 , 13, 1800454	2.5	13
35	Demonstrating the Ultrathin Metal/Insulator/Metal Diode Using TiN/ZrO ₂ /Al ₂ O ₃ /ZrO ₂ Stack by Employing RuO ₂ Top Electrode. <i>IEEE Transactions on Electron Devices</i> , 2018 , 65, 660-666	2.9	12
34	Physisorbed-precursor-assisted atomic layer deposition of reliable ultrathin dielectric films on inert graphene surfaces for low-power electronics. <i>2D Materials</i> , 2016 , 3, 035027	5.9	12
33	Electrical Properties of ZrO ₂ /Al ₂ O ₃ /ZrO ₂ -Based Capacitors with TiN, Ru, and TiN/Ru Top Electrode Materials. <i>Physica Status Solidi - Rapid Research Letters</i> , 2018 , 12, 1800356	2.5	12
32	Improved performance and stability of In-Sn-Zn-O thin film transistor by introducing a meso-crystalline ZrO ₂ high-k gate insulator. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , 2019 , 37, 020924	2.9	10
31	Asymmetry in electrical properties of Al-doped TiO ₂ film with respect to bias voltage. <i>Physica Status Solidi - Rapid Research Letters</i> , 2015 , 9, 410-413	2.5	9
30	Optimization of chemical structure of Schottky-type selection diode for crossbar resistive memory. <i>ACS Applied Materials & Interfaces</i> , 2012 , 4, 5338-45	9.5	9
29	The impact of plasma-enhanced atomic layer deposited ZrSiO _x insulators on low voltage operated In-Sn-Zn-O thin film transistors. <i>Ceramics International</i> , 2019 , 45, 19166-19172	5.1	8
28	Atomic layer deposition of Ru thin films using (2,4-dimethyloxopentadienyl)(ethylcyclopentadienyl)Ru and the effect of ammonia treatment during the deposition. <i>Journal of Materials Chemistry C</i> , 2020 , 8, 6993-7004	7.1	8
27	Reducing the nano-scale defect formation of atomic-layer-deposited SrTiO ₃ films by adjusting the cooling rate of the crystallization annealing of the seed layer. <i>Thin Solid Films</i> , 2015 , 589, 723-729	2.2	8

26	Modulated filamentary conduction of Ag/TiO ₂ core-shell nanowires to impart extremely sustained resistance switching behavior in a flexible composite. <i>Applied Materials Today</i> , 2020 , 19, 100569	6.6	7
25	Chemistry of SiN _x thin film deposited by plasma-enhanced atomic layer deposition using di-isopropylaminosilane (DIPAS) and N ₂ plasma. <i>Ceramics International</i> , 2018 , 44, 20890-20895	5.1	6
24	Controlling the Current Conduction Asymmetry of HfO ₂ Metal-Insulator-Metal Diodes by Interposing Al ₂ O ₃ Layer. <i>IEEE Transactions on Electron Devices</i> , 2019 , 66, 402-406	2.9	6
23	Substrate Effects on the Growth Behavior of Atomic-Layer-Deposited Ru Thin Films Using RuO ₄ Precursor and N ₂ /H ₂ Mixed Gas. <i>Journal of Physical Chemistry C</i> , 2019 , 123, 22539-22549	3.8	5
22	Scaling the Equivalent Oxide Thickness by Employing a TiO ₂ Thin Film on a ZrO ₂ /Al ₂ O ₃ -Based Dielectric for Further Scaling of Dynamic Random Access Memory. <i>Physica Status Solidi - Rapid Research Letters</i> , 2019 , 13, 1900282	2.5	5
21	Improving the photoresponsivity and reducing the persistent photocurrent effect of visible-light ZnO/quantum-dot phototransistors via a TiO ₂ layer. <i>Journal of Materials Chemistry C</i> , 2020 , 8, 16384-16391	7.1	5
20	A visible-light phototransistor based on the heterostructure of ZnO and TiO with trap-assisted photocurrent generation.. <i>RSC Advances</i> , 2021 , 11, 12051-12057	3.7	4
19	Improving the photodetection and stability of a visible-light QDs/ZnO phototransistor via an Al ₂ O ₃ additional layer. <i>Journal of Materials Chemistry C</i> , 2021 , 9, 2550-2560	7.1	4
18	Y-doped HfO ₂ deposited by atomic layer deposition using a cocktail precursor for DRAM capacitor dielectric application. <i>Ceramics International</i> , 2021 , 48, 3236-3236	5.1	3
17	Optimization of a SiO _x /SiN _x O _y C _z multilayer structure for a reliable gas diffusion barrier via low-temperature plasma-enhanced atomic layer deposition. <i>Ceramics International</i> , 2019 , 45, 7407-7412	5.1	3
16	Resistive Memory: 32 B2 Crossbar Array Resistive Memory Composed of a Stacked Schottky Diode and Unipolar Resistive Memory (Adv. Funct. Mater. 11/2013). <i>Advanced Functional Materials</i> , 2013 , 23, 1350-1350	15.6	2
15	Sustainable resistance switching performance from composite-type ReRAM device based on carbon Nanotube@Titania core-shell wires. <i>Scientific Reports</i> , 2020 , 10, 18830	4.9	2
14	Investigating the interface characteristics of high-k ZrO ₂ /SiO ₂ stacked gate insulator grown by plasma-enhanced atomic layer deposition for improving the performance of InSnZnO thin film transistors. <i>AIP Advances</i> , 2020 , 10, 015239	1.5	1
13	The Significance on Structural Modulation of Buffer and Gate Insulator for ALD Based InGaZnO TFT Applications. <i>IEEE Transactions on Electron Devices</i> , 2021 , 1-7	2.9	1
12	Comparative Study on the Gate-Induced Electrical Instability of p-Type SnO Thin-Film Transistors with SiO ₂ and Al ₂ O ₃ /SiO ₂ Gate Dielectrics. <i>Physica Status Solidi - Rapid Research Letters</i> , 2020 , 14, 2000304	2.5	1
11	Nanoscale surface engineering of a high-k ZrO ₂ /SiO ₂ gate insulator for a high performance ITZO TFT via plasma-enhanced atomic layer deposition. <i>Journal of Materials Chemistry C</i> , 2020 , 8, 13342-13348	7.1	1
10	Highly sustainable mechanical/electrical resistance switching behaviors via one-dimensional Ag/TiO ₂ core-shell resistive switchable materials in flexible composite. <i>Organic Electronics</i> , 2021 , 88, 105968	3.5	1
9	An Empirical Investigation on the Effect of Oxygen Vacancy in ZrO ₂ Thin Film on the Frequency-Dependent Capacitance Degradation in the Metal-Insulator-Metal Capacitor. <i>IEEE Transactions on Electron Devices</i> , 2021 , 1-5	2.9	1

8	Optimized Al-doped TiO ₂ gate insulator for a metal-oxide-semiconductor capacitor on a Ge substrate. <i>Journal of Materials Chemistry C</i> , 2021 , 9, 1572-1583	7.1	1
7	Resistance Switching Capable Polymer Nanocomposites Employing Networks of One-Dimensional Nanocarbon Wrapped by TiO ₂ Conformal Layer. <i>IEEE Nanotechnology Magazine</i> , 2018 , 17, 567-573	2.6	0
6	Depletion effect of polycrystalline-silicon gate electrode by phosphorus deactivation. <i>Solid-State Electronics</i> , 2017 , 127, 1-4	1.7	0
5	Chemistry of ruthenium as an electrode for metal-insulator-metal capacitor application. <i>Nanotechnology</i> , 2021 , 32, 045201	3.4	0
4	Improved Properties of the Atomic Layer Deposited Ru Electrode for Dynamic Random-Access Memory Capacitor Using Discrete Feeding Method. <i>ACS Applied Materials & Interfaces</i> , 2021 , 13, 23915-23927	9.5	0
3	Modulation of the adsorption chemistry of a precursor in atomic layer deposition to enhance the growth per cycle of a TiO thin film. <i>Physical Chemistry Chemical Physics</i> , 2021 , 23, 2568-2574	3.6	0
2	Nanosession: Atomic Layer Deposition419-428		
1	Controlling the crystallinity of HfO ₂ thin film using the surface energy-driven phase stabilization and template effect. <i>Applied Surface Science</i> , 2022 , 590, 153082	6.7	